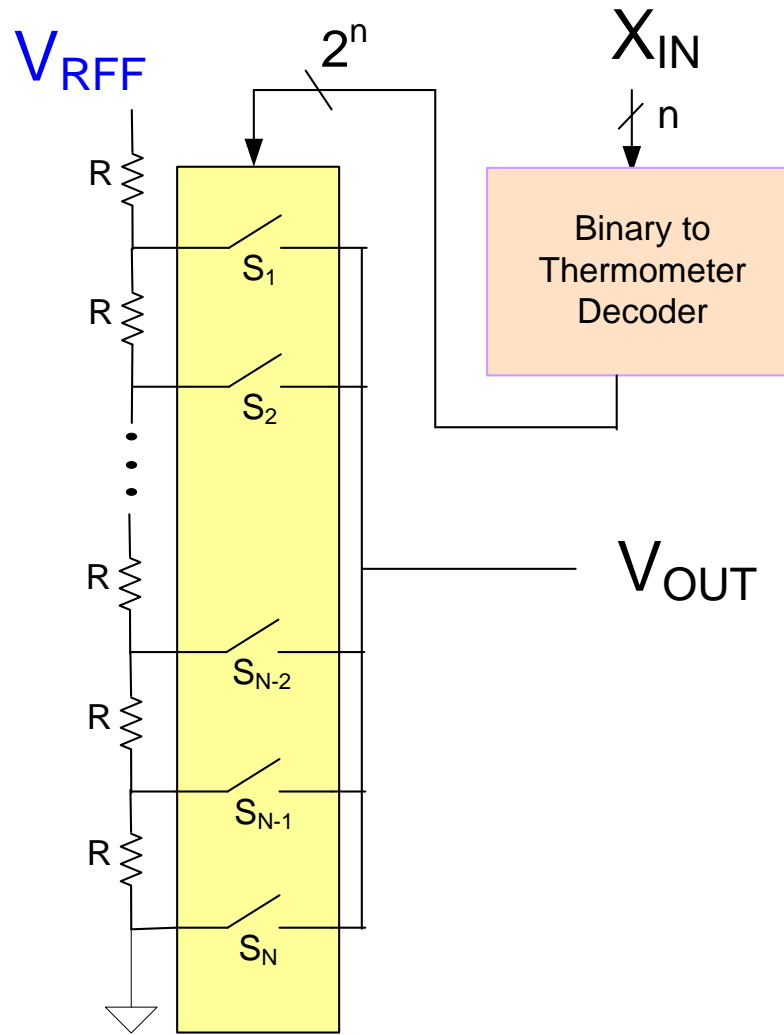


# EE 435

## Lecture 32

- Switch Implementation
- Current Steering DACs

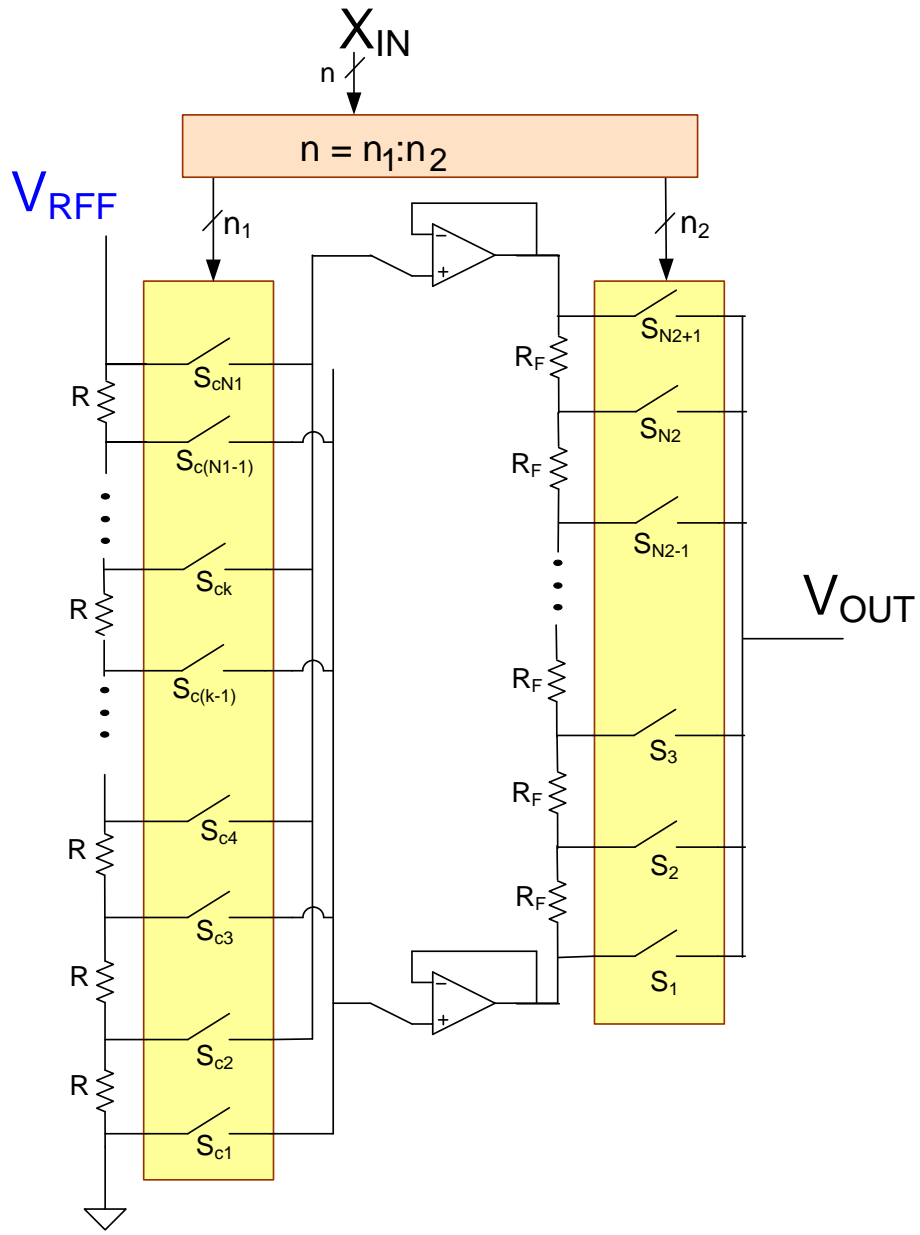
# R-String DAC



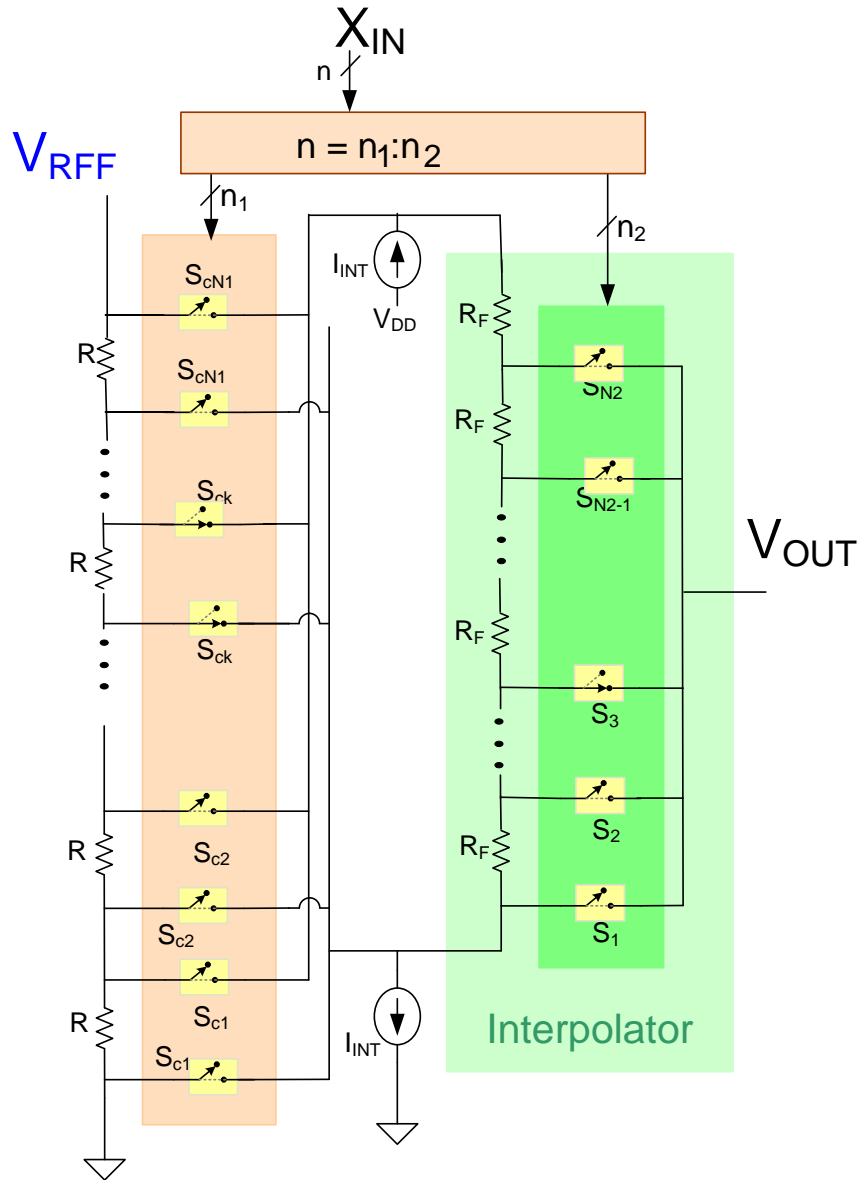
**Basic R-String DAC including Logic to Control Switches**

# Review from Last Lecture

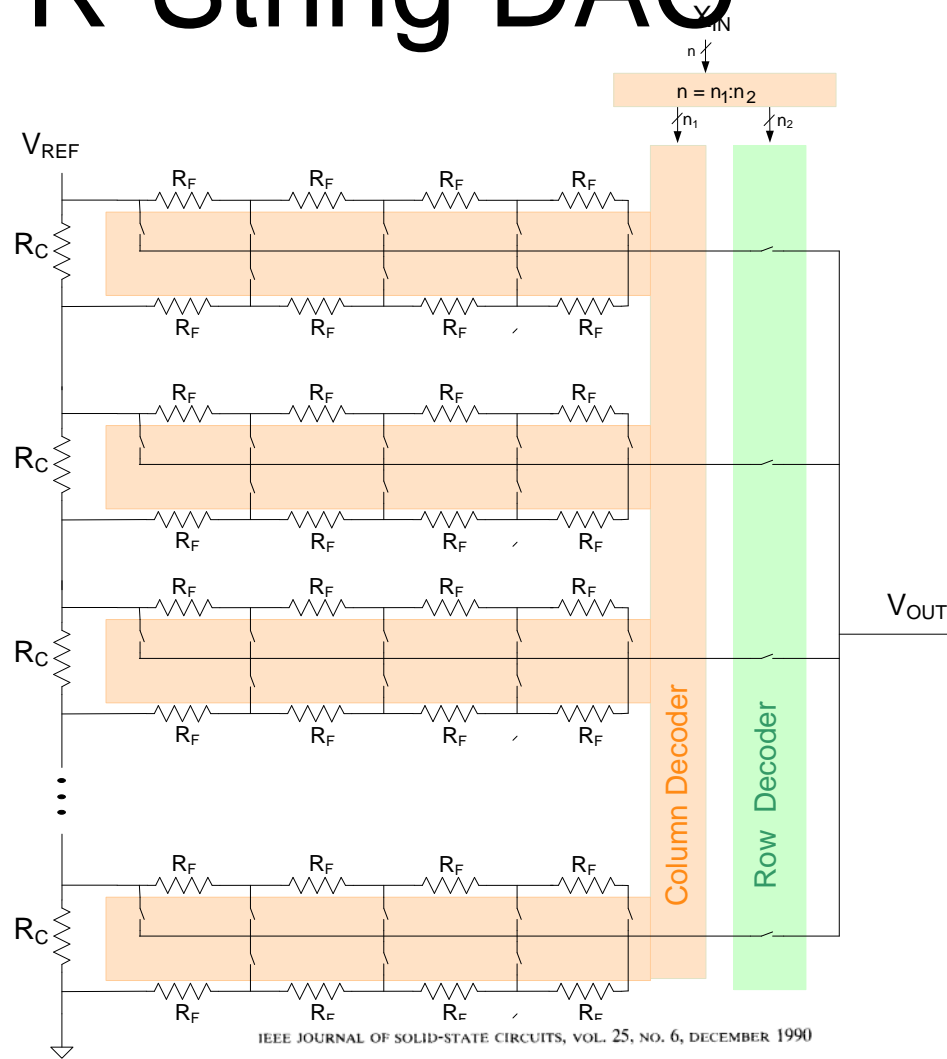
# R-String DAC



# R-String DAC



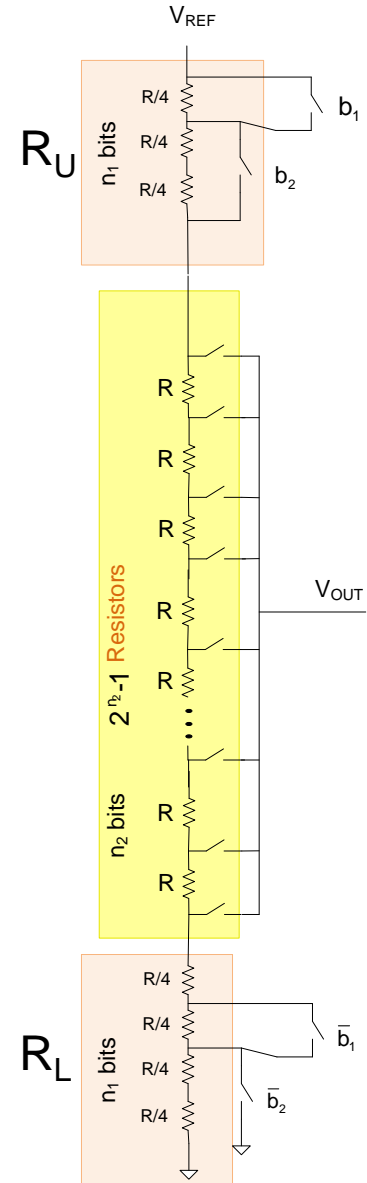
# R-String DAC



**Note Dual Ladder is used !**

**A 10-b 50-MHz CMOS D/A Converter  
with 75-Ω Buffer**

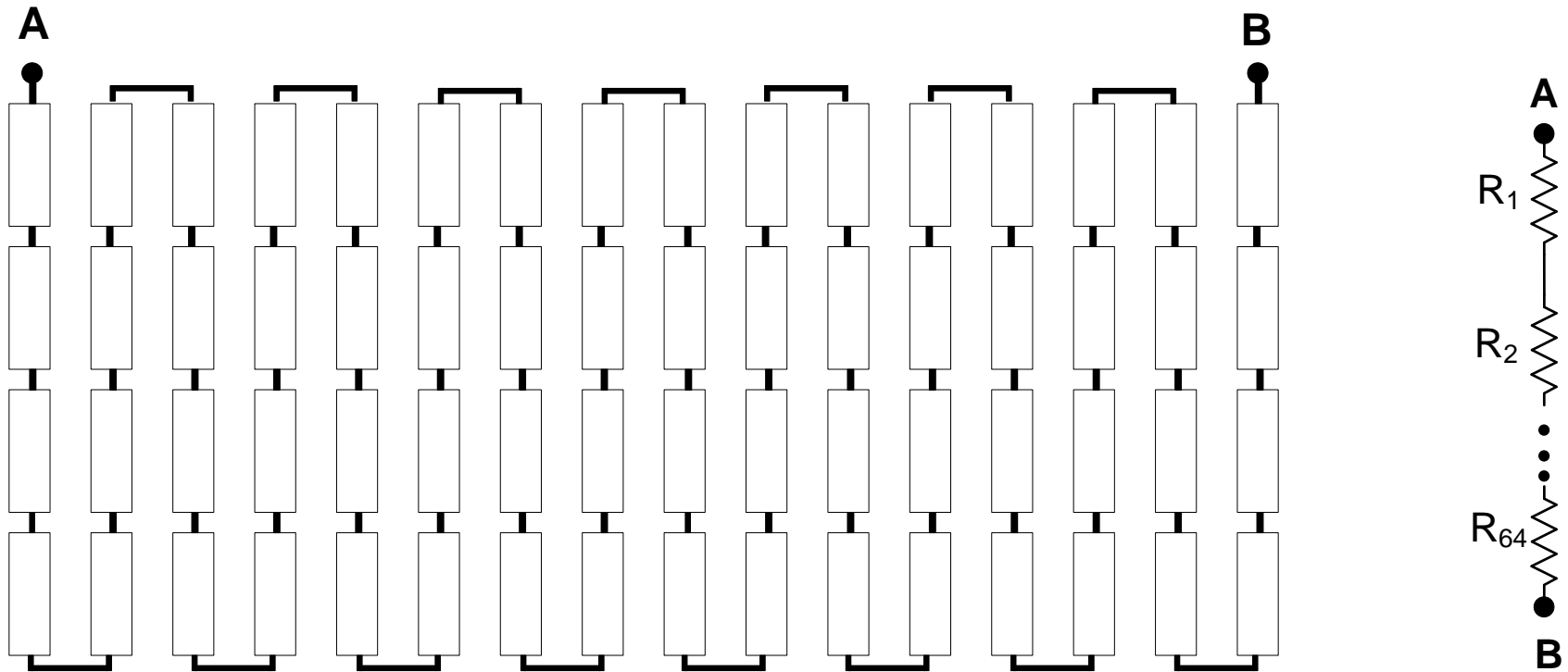
# Basic R-String DAC



For all  $b_1$  and  $b_2$ ,  $R_U + R_L = R$

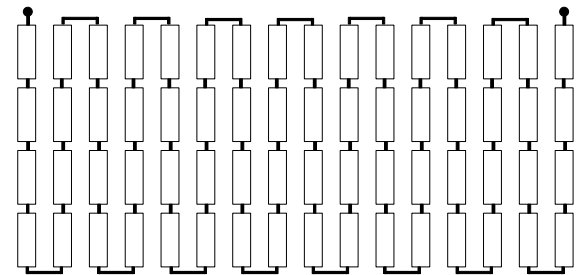
- Another Segmented DAC structure
- Can be viewed as a “dither” DAC
- Often  $n_1$  is much smaller than  $n_2$
- Dither can be used in other applications as well

# Resistor Layout

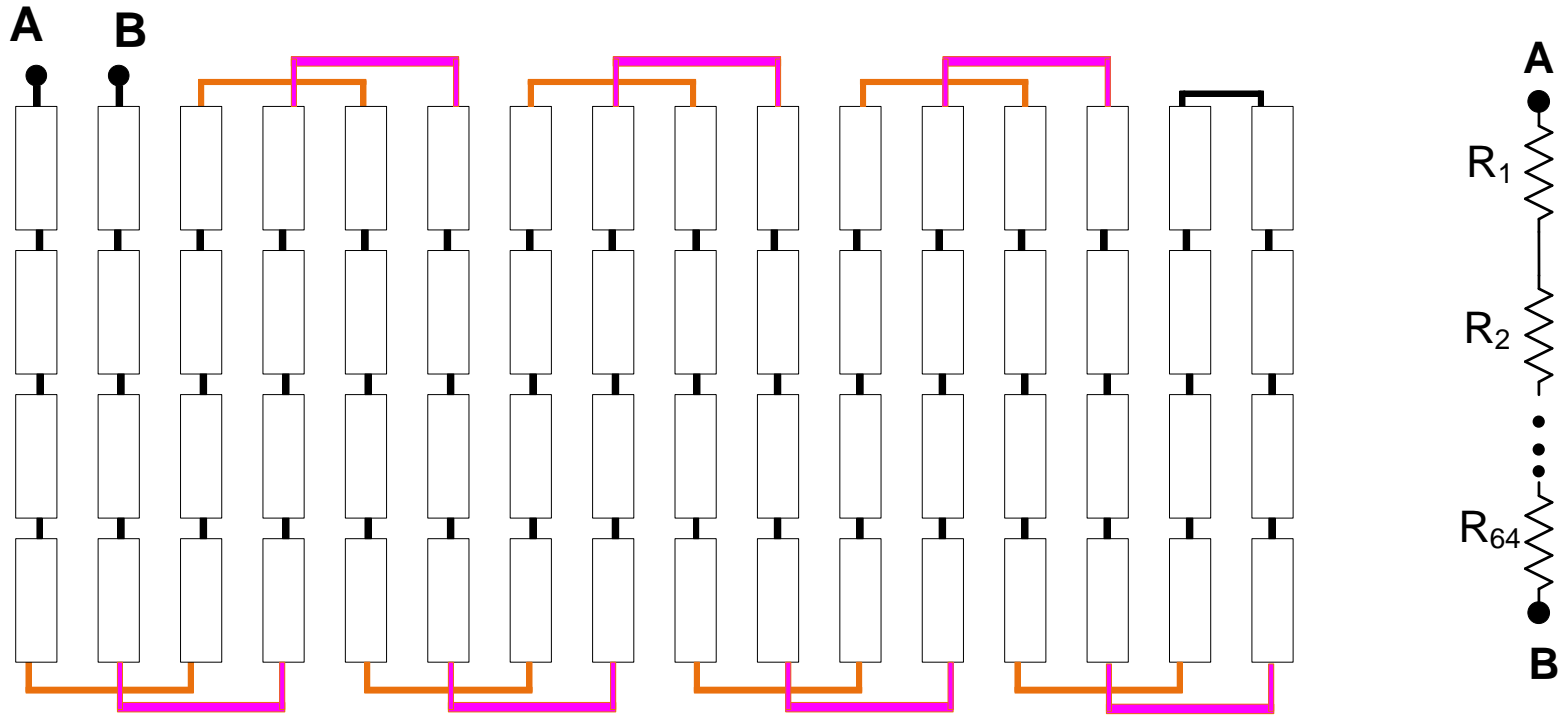


Standard Series Layout of 64 resistors

# Resistor Layout



## Correction on Terminology



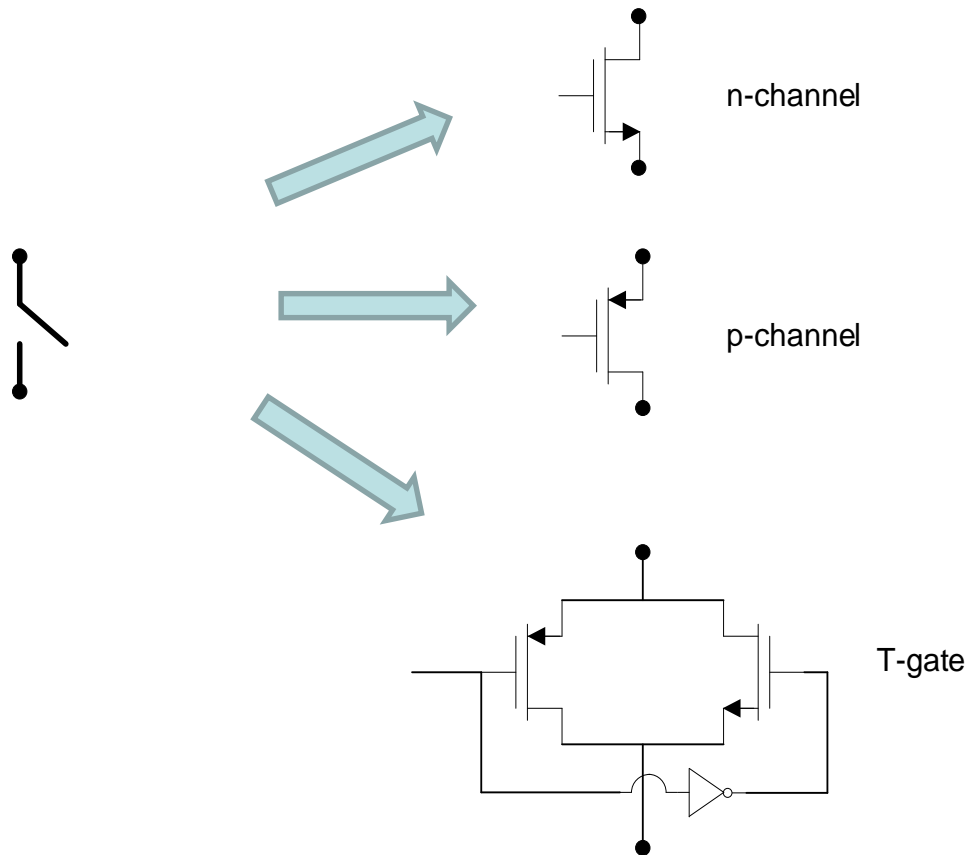
Layout of 64 resistors with reduced gradient sensitivity



# Switches used extensively in data converters !

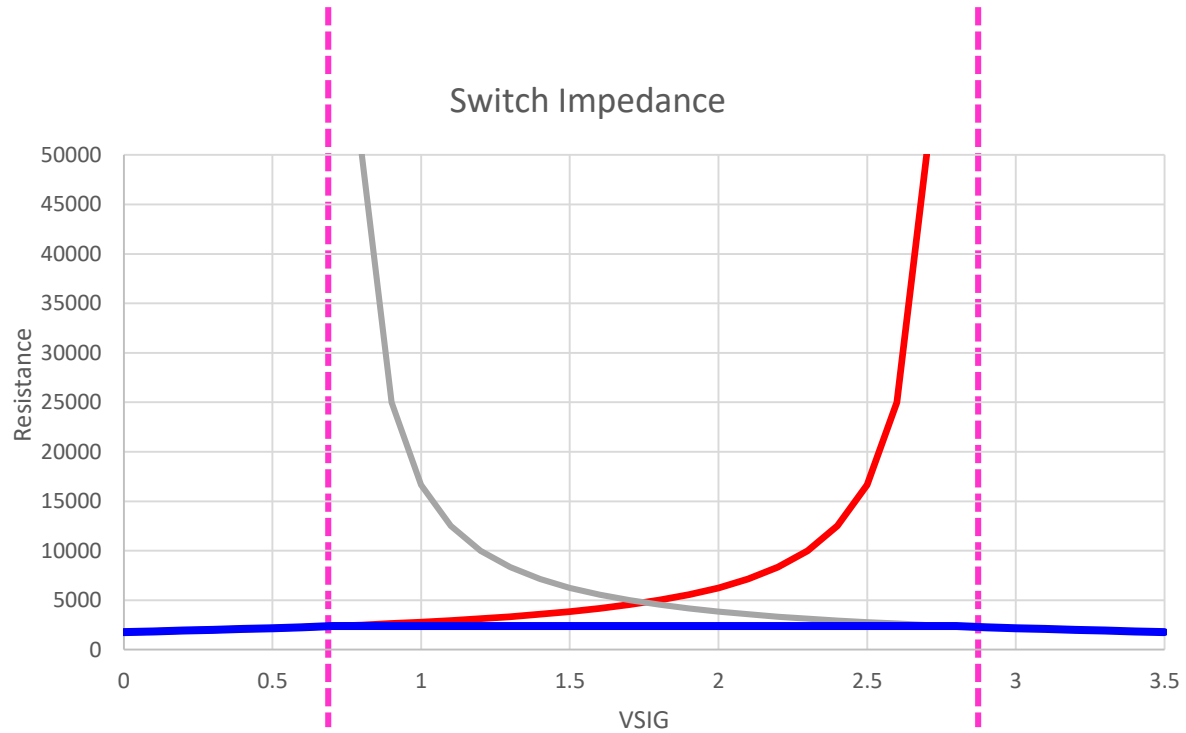
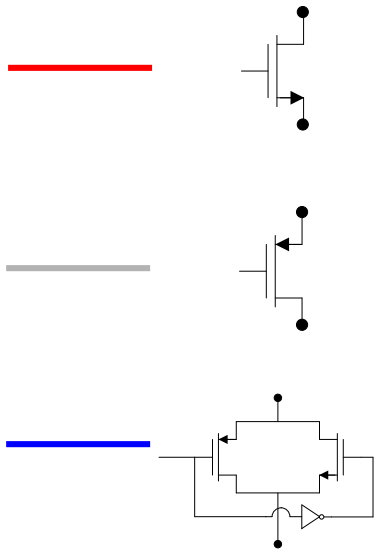
## Switch Implementation Issues

### Basic Simple Switches



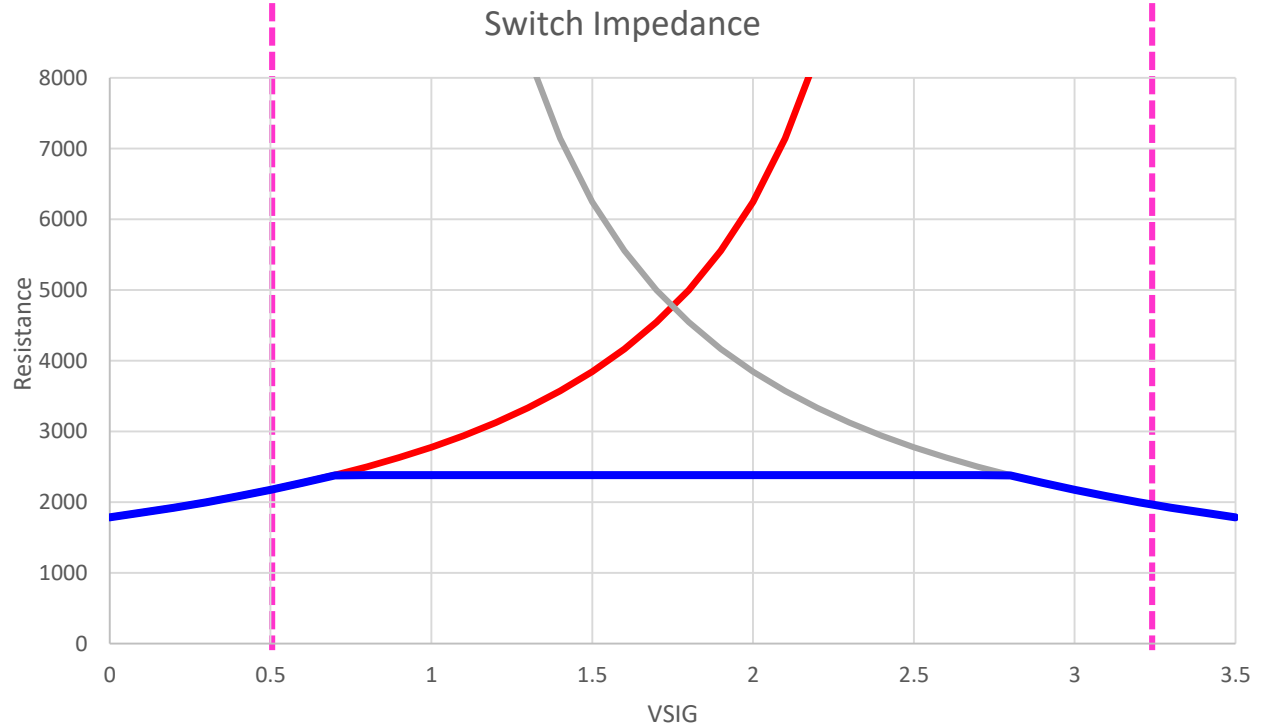
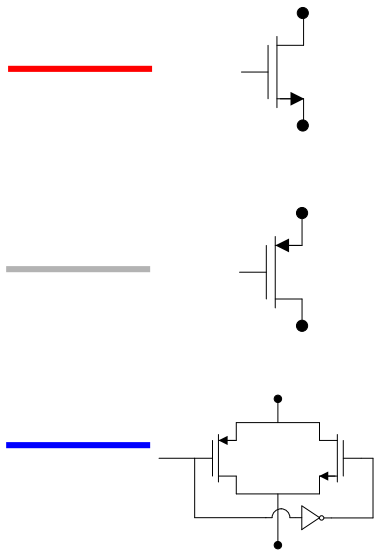
# Switch Implementation Issues

$V_{THn}=0.7$   
 $V_{THp}=-0.7$   
 $W_p=3W_n$   
 $L_p=L_n$   
 $V_{DD}=3.5V$



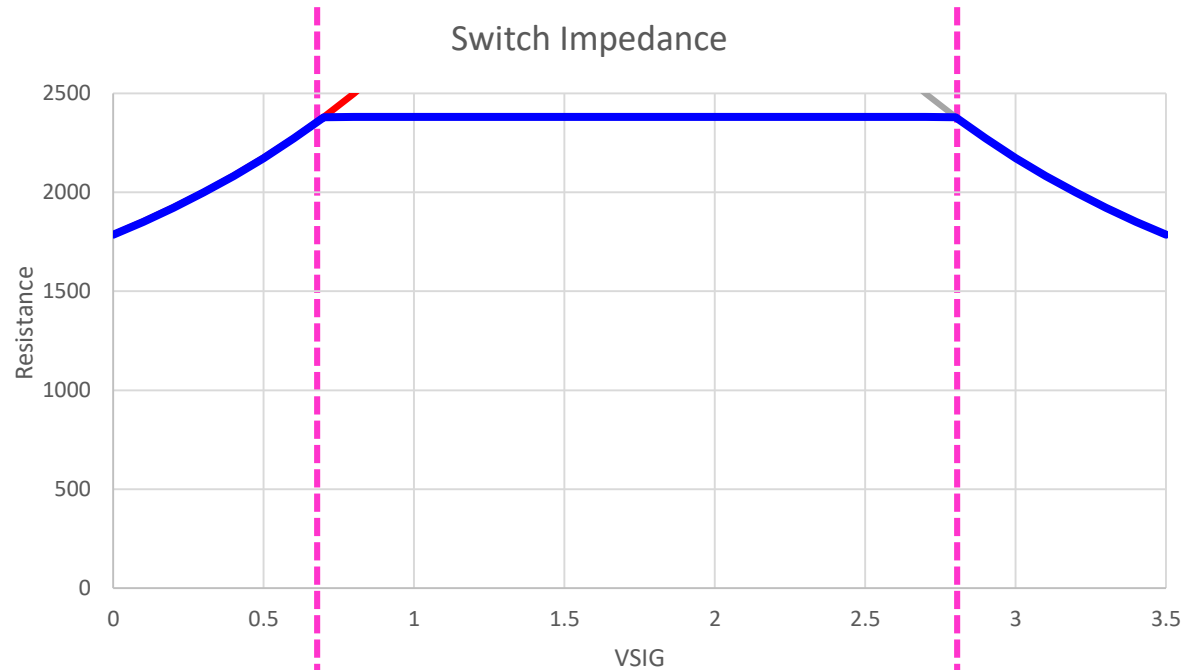
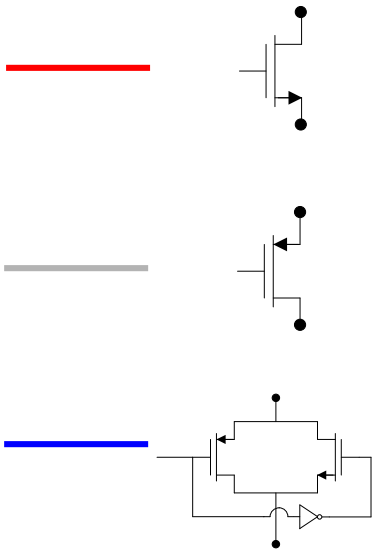
# Switch Implementation Issues

$V_{THn}=0.7$   
 $V_{THp}=-0.7$   
 $W_p=3W_n$   
 $L_p=L_n$   
 $V_{DD}=3.5V$



# Switch Implementation Issues

$V_{THn}=0.7$   
 $V_{THp}=-0.7$   
 $W_p=3W_n$   
 $L_p=L_n$   
 $V_{DD}=3.5V$

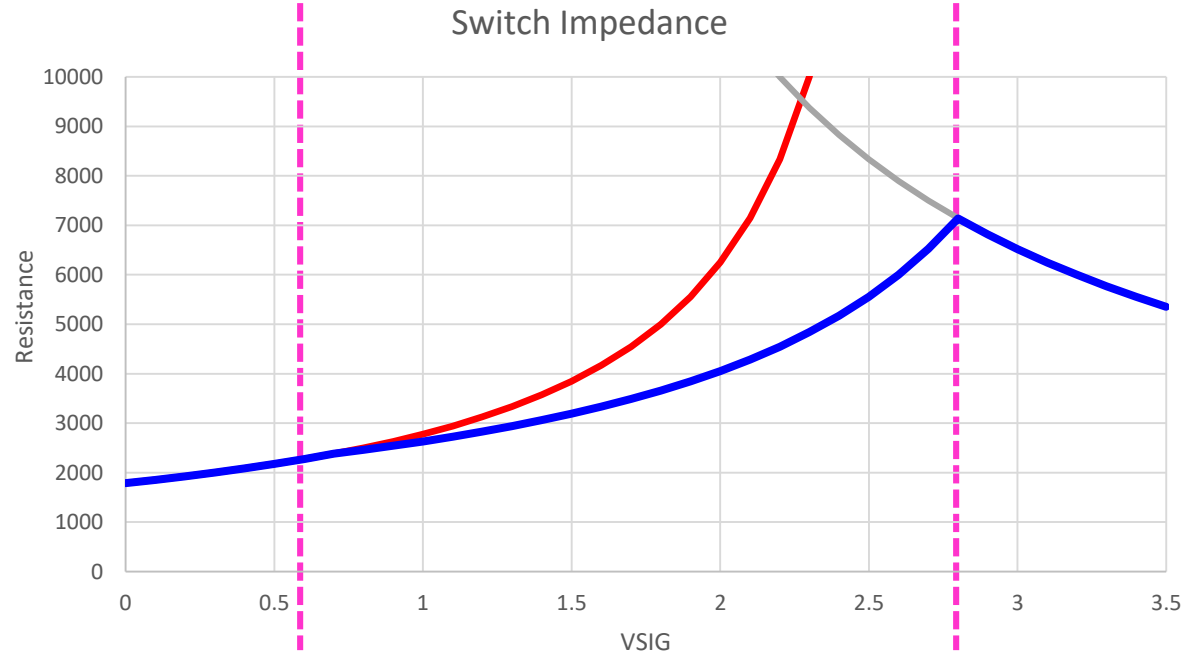
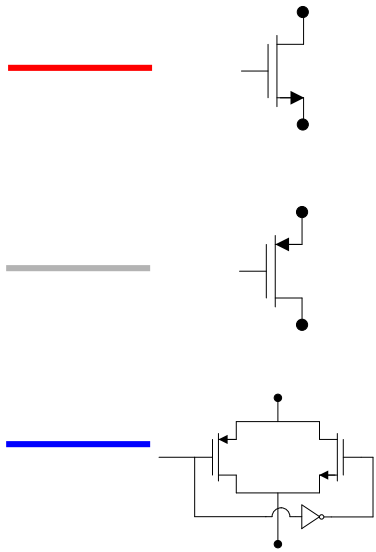


Transmission Gate Impedance Can be Reasonably constant

# Switch Implementation Issues

## Equal-Sized Switches

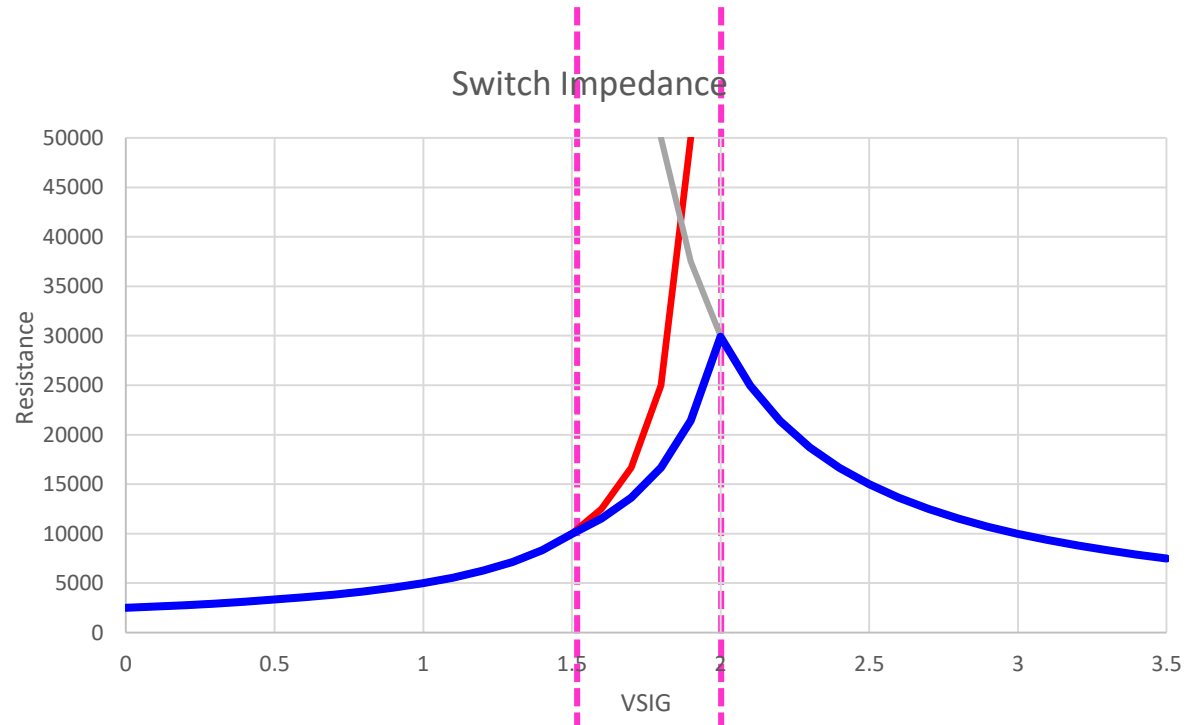
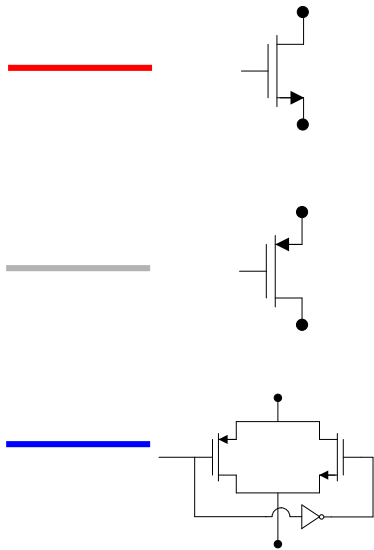
$V_{THn}=0.7$   
 $V_{THp}=-0.7$   
 $W_p=W_n$   
 $L_p=L_n$   
 $V_{DD}=3.5V$



# Switch Implementation Issues

Equal-Sized Switches  
High Threshold Voltages

$V_{THn}=1.50$   
 $V_{THp}=-1.5$   
 $W_p=W_n$   
 $L_p=L_n$   
 $V_{DD}=3.5V$

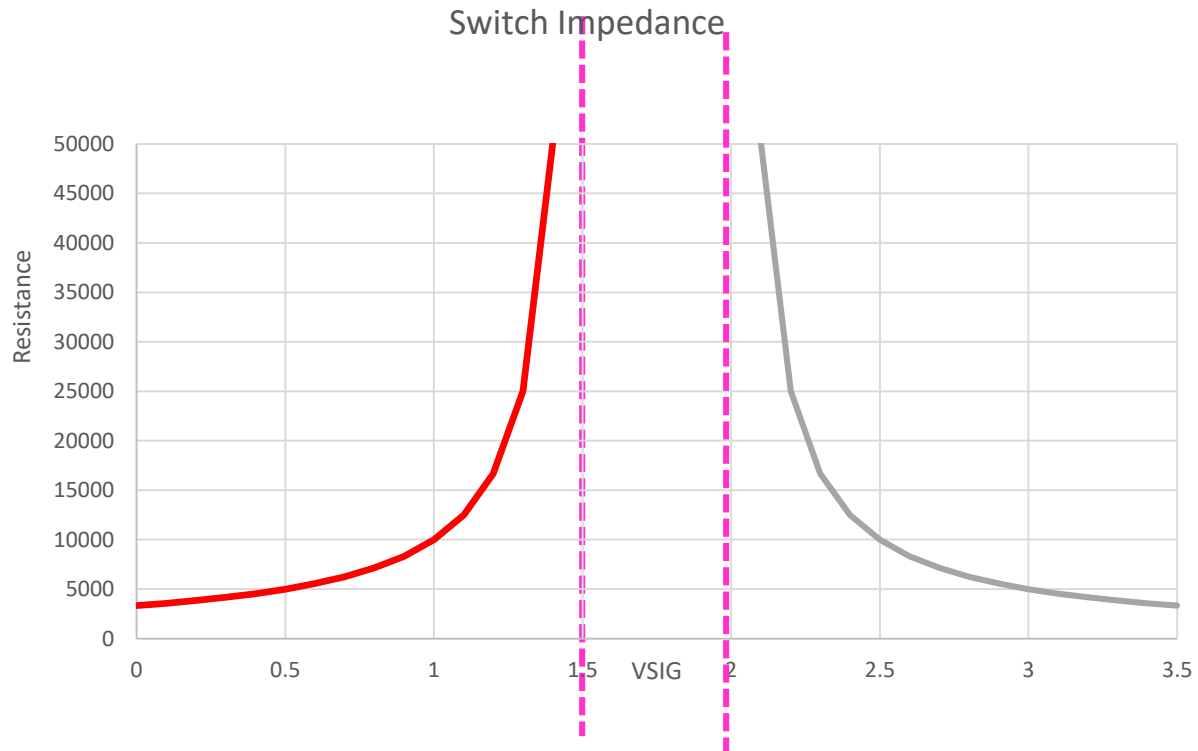
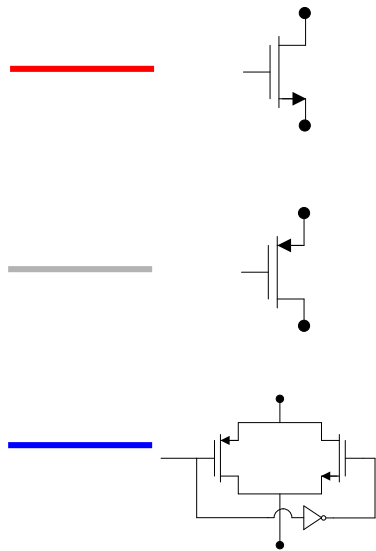


Even Transmission Gate Does Not Perform Well

# Switch Implementation Issues

$$\begin{aligned}V_{THn} &= 2.0 \\ V_{THp} &= -2.0 \\ W_p &= 3W_n \\ L_p &= L_n \\ V_{DD} &= 3.5V\end{aligned}$$

Tough unlikely, this is what would happen if very high threshold devices were used



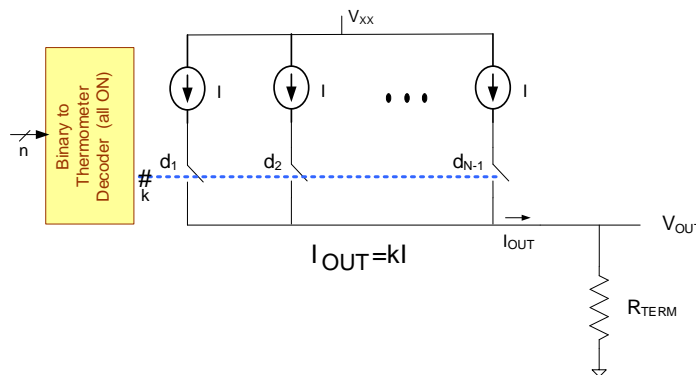
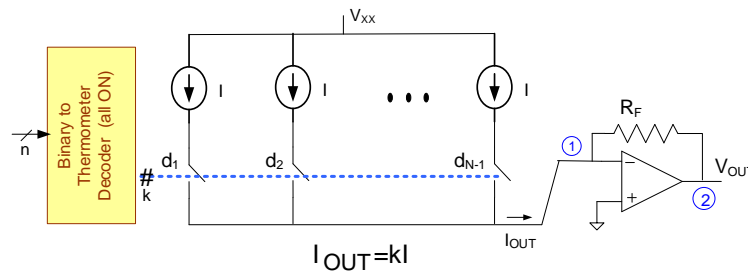
Gap where neither switch is working

# Current Steering DACs

Current will be “steered” to a resistive load (on chip)

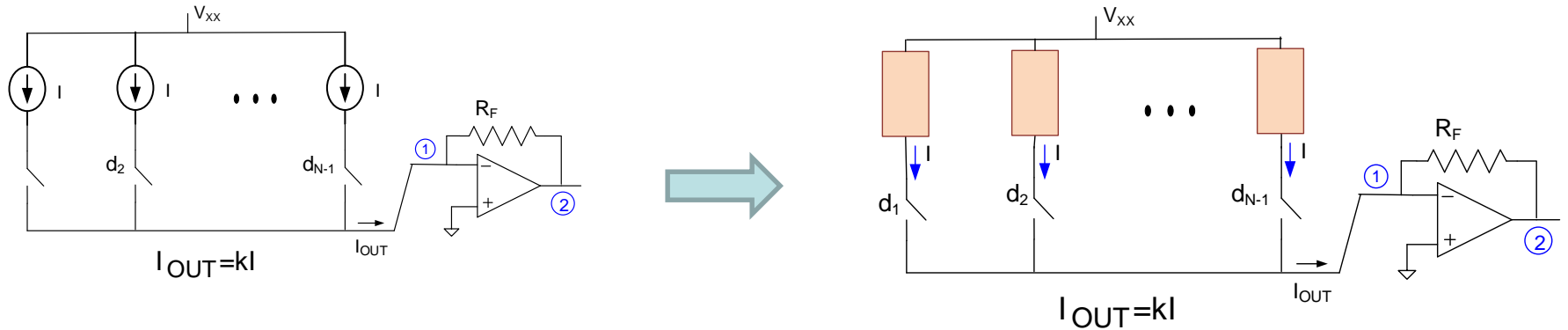
Output could be a current (user supplies load)

## Basic Concept of Current Steering DACs

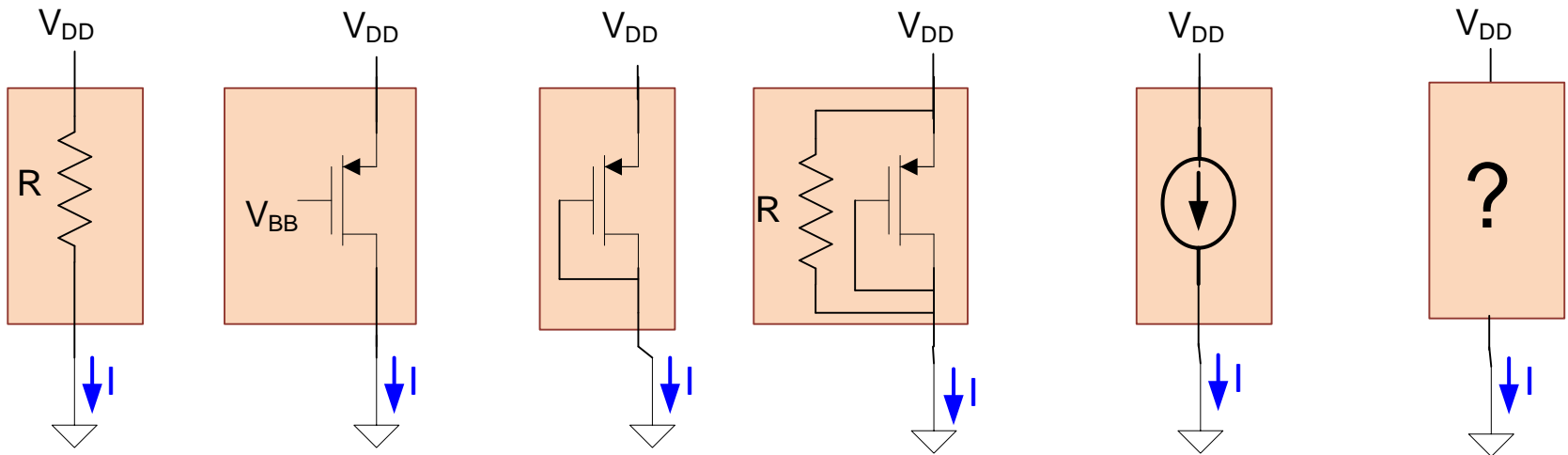




# Current Steering DACs

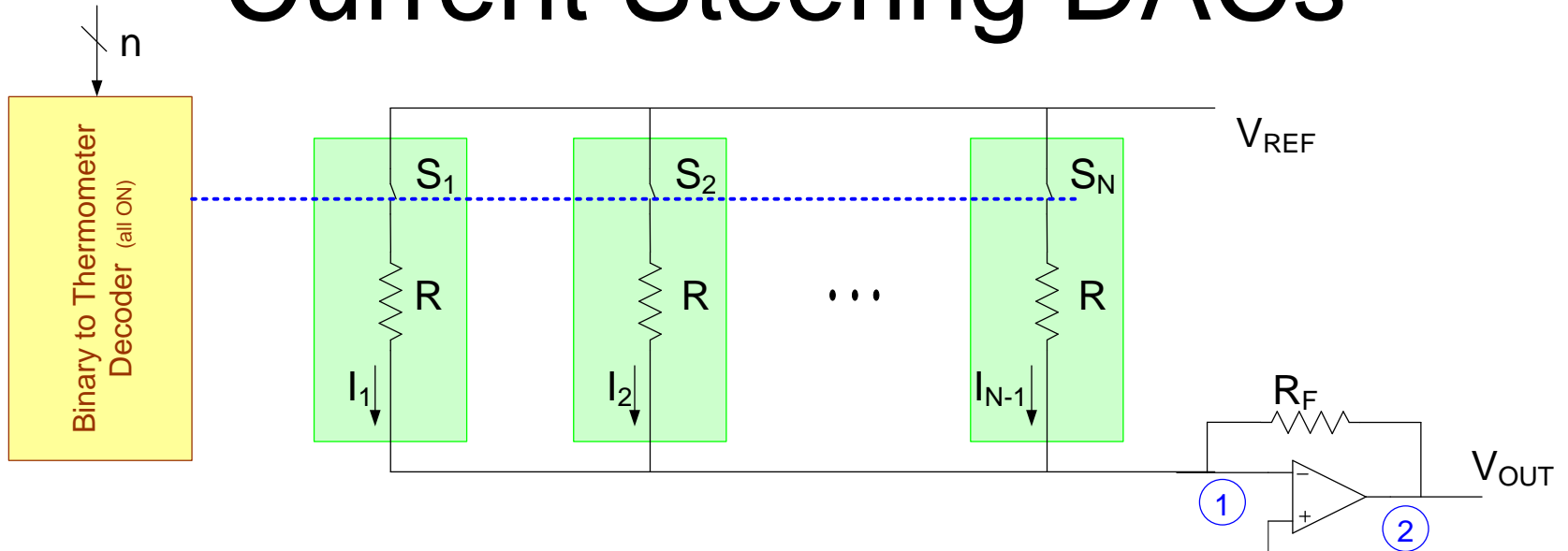


What is important is the current generated, not whether it comes from a “current source”



Many potential current generator blocks, just require that all be ideally identical

# Current Steering DACs

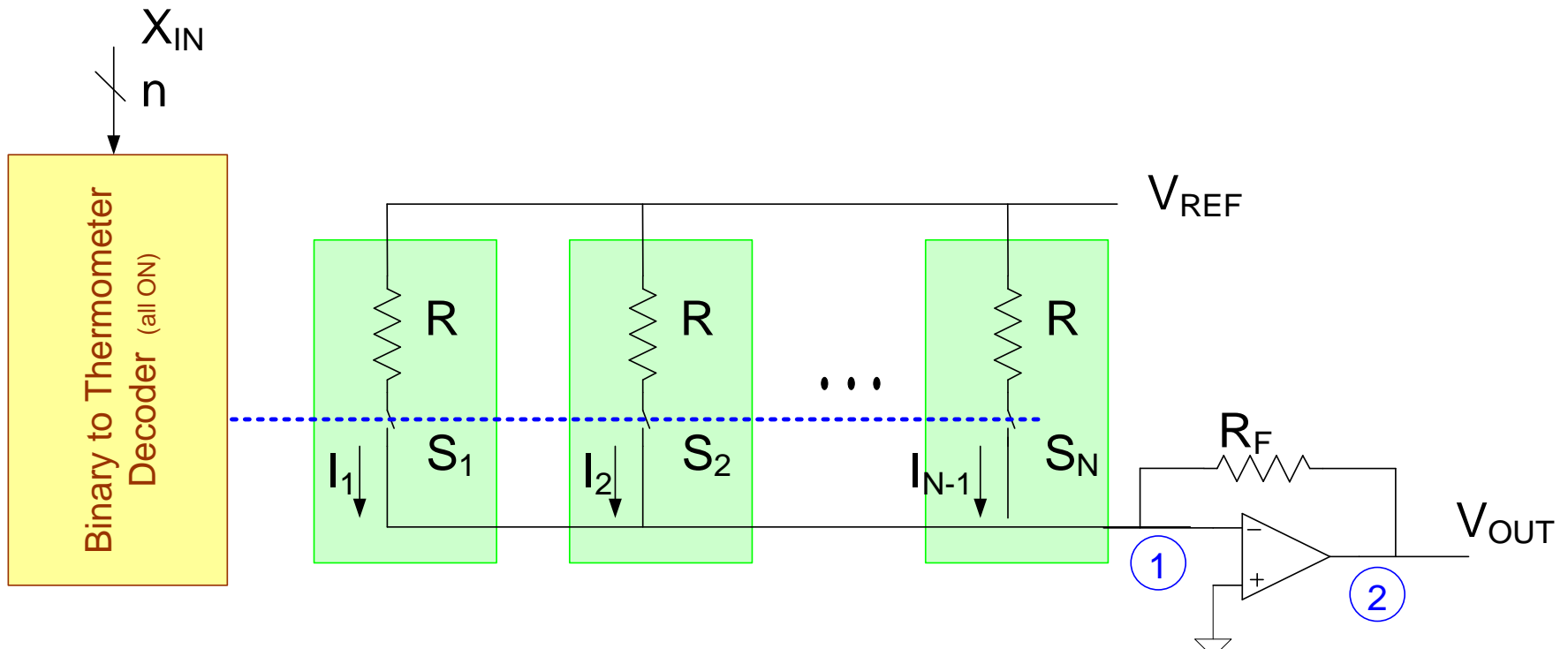


## Inherently Insensitive to Nonlinearities in Switches and Resistors

- Termed “top plate switching”
- Thermometer coding
- Excellent DNL properties
- INL may be poor, typically near mid range
- INL is a random variable with variance approximately proportional to area
- Area gets large for good yield with large  $n$
- Each additional bit of resolution requires a factor of 2 increase in area if same sized resistors are used
- Each additional bit of resolution requires another factor of 4 increase in area to maintain the same yield

$$\sigma = \frac{A_{PEL}}{\sqrt{A}}$$

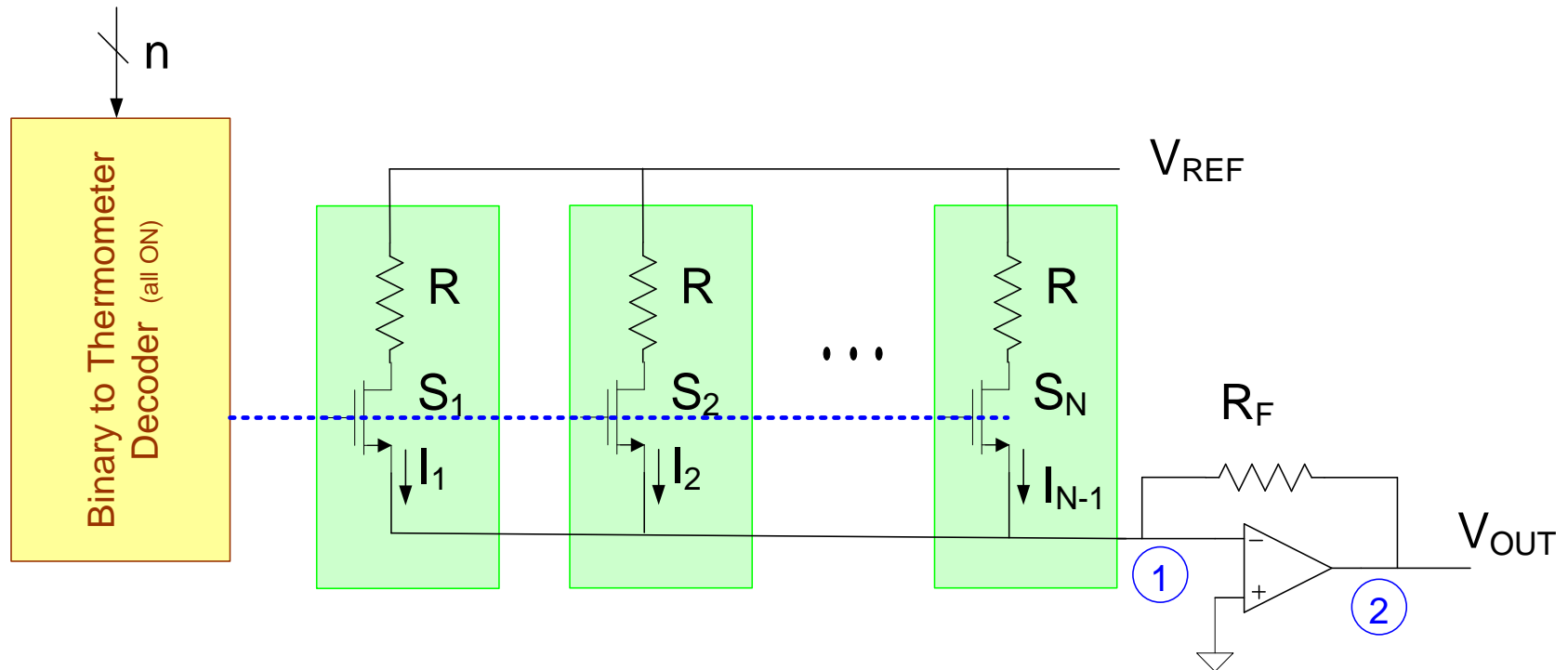
# Current Steering DACs



**Inherently Insensitive to Nonlinearities in Switches and Resistors**  
**Smaller ON resistance and less phase-shift from clock edges**

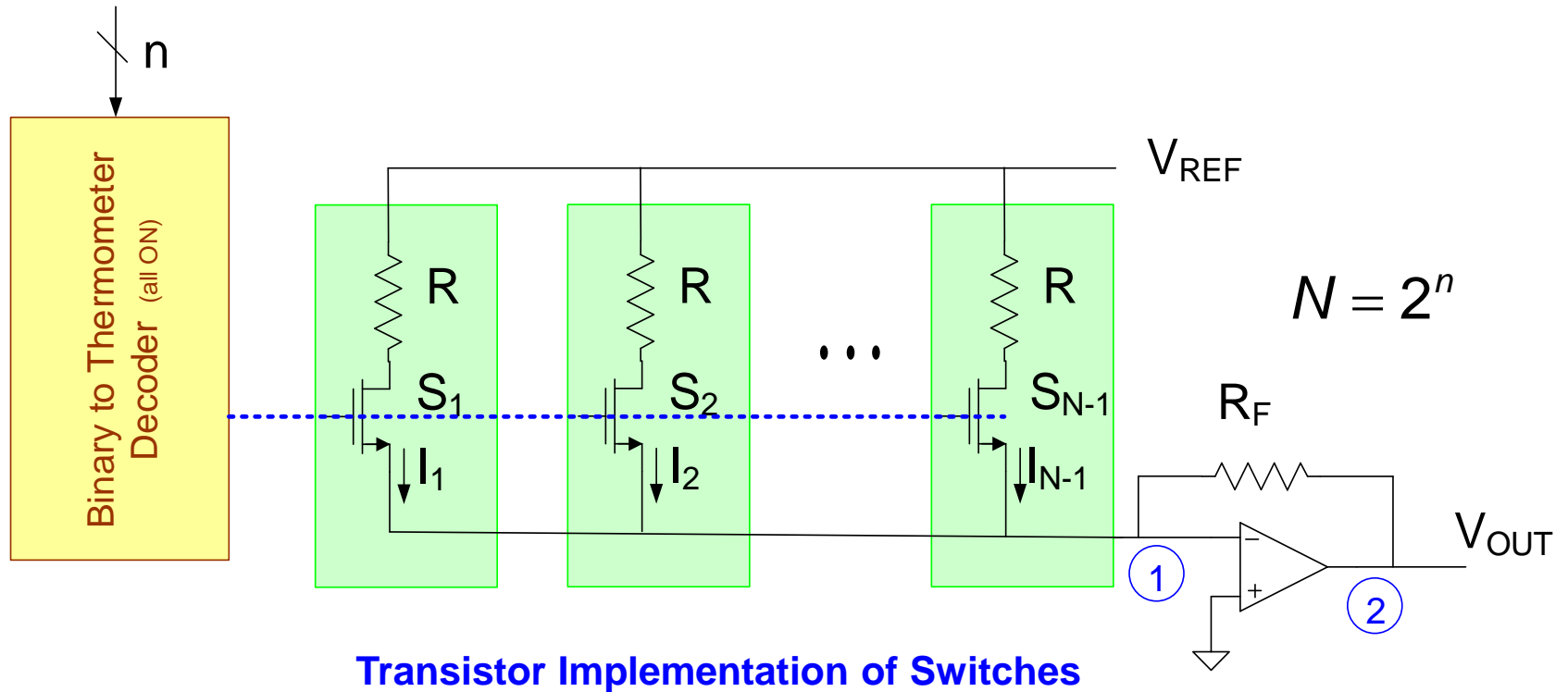
- Termed “bottom plate switching”
- Thermometer coded

# Current Steering DACs



Transistor Implementation of Switches

# Current Steering DACs



How should the op amp be compensated?

Assume k switches are on  $0 < k < N-1$

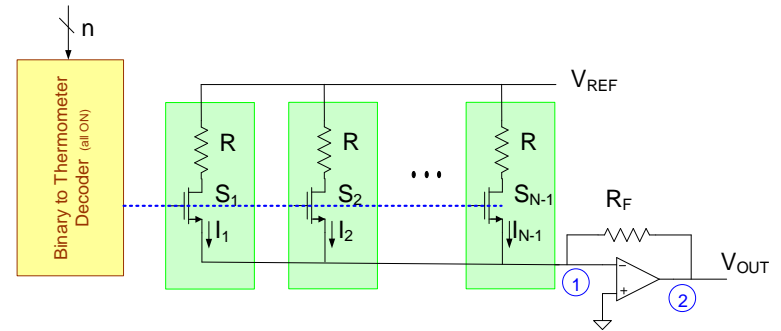
$$\beta = \frac{\frac{R_{CELL}}{k}}{\frac{R_{CELL} + R_F}{k}} = \frac{R_{CELL}}{R_{CELL} + kR_F}$$

If  $V_{OUTFS} = V_{REF}$   $R_{CELL} = NR_F$

$$0.5 < \beta \leq 1$$

# How should the op amp be compensated?

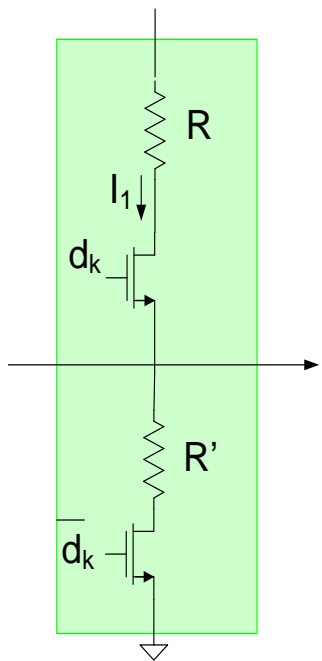
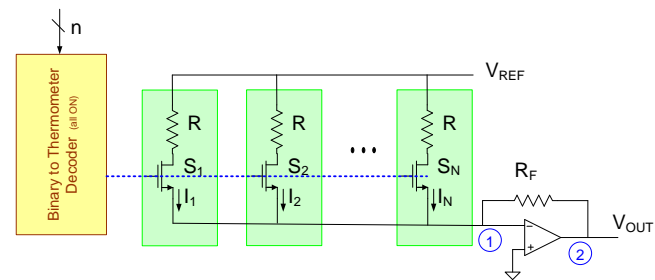
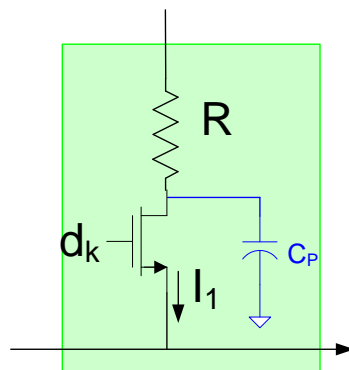
$$\beta = \frac{\frac{R_{\text{CELL}}}{k}}{\frac{R_{\text{CELL}}}{k} + R_{\text{F}}} = \frac{R_{\text{CELL}}}{R_{\text{CELL}} + kR_{\text{F}}}$$



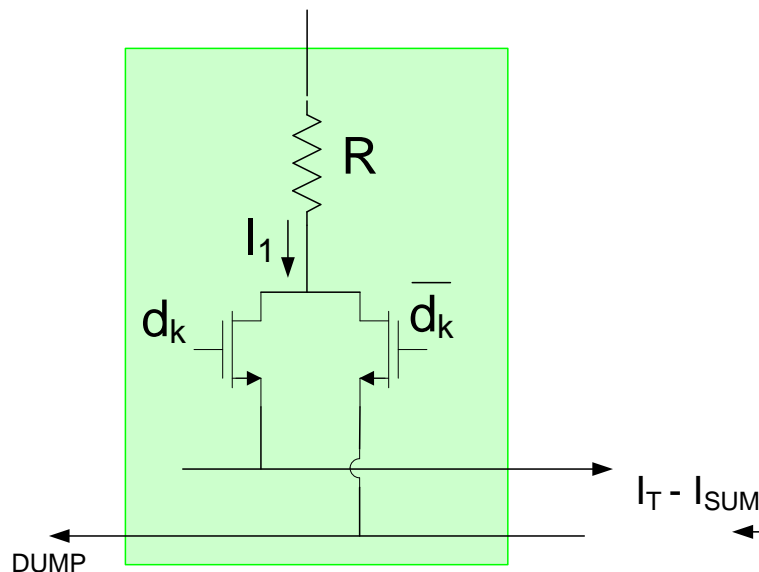
$$V_{\text{OUTFS}} = V_{\text{REF}}$$

$$0.5 < \beta \leq 1$$

# Current Steering DACs



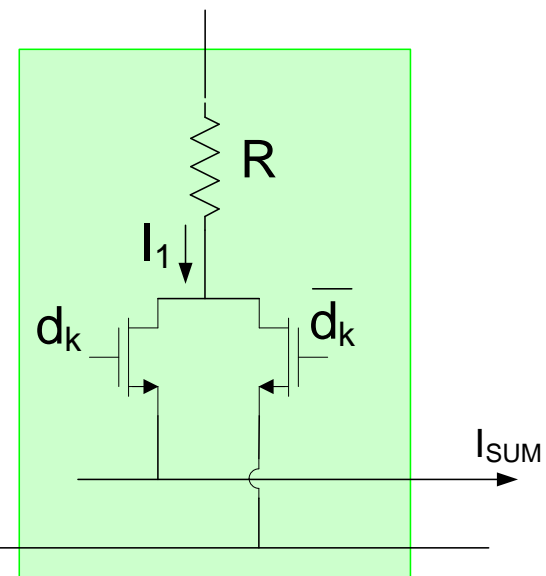
$\beta$  Compensation



DUMP

$I_T - I_{SUM}$

$C_P$  Compensation

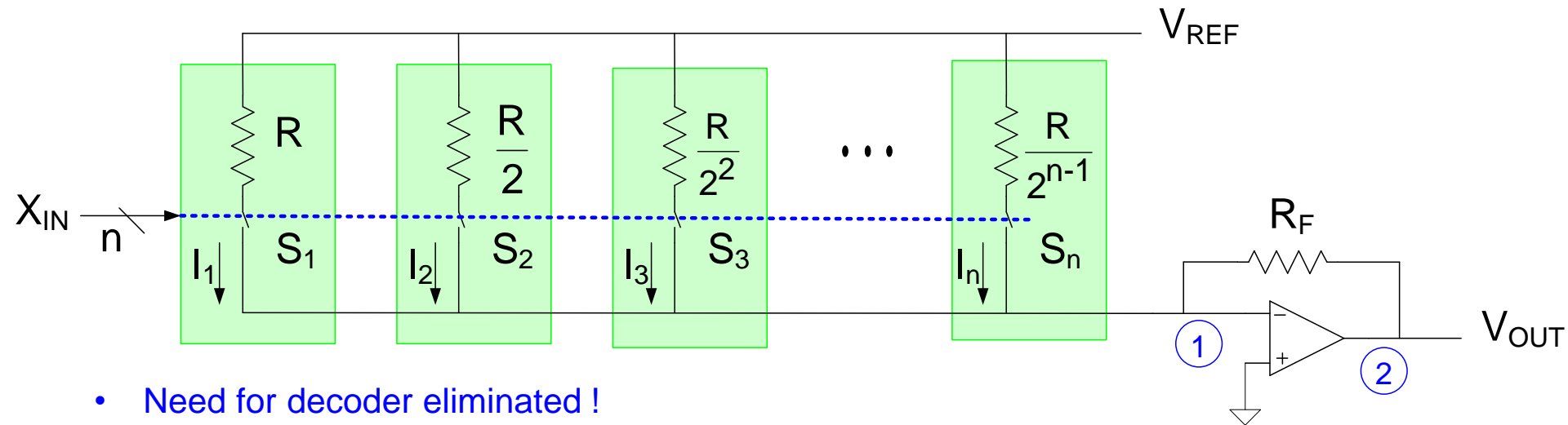


$I_{SUM}$

Differential Output

# Current Steering DACs

## Binary-Weighted Resistor Arrays

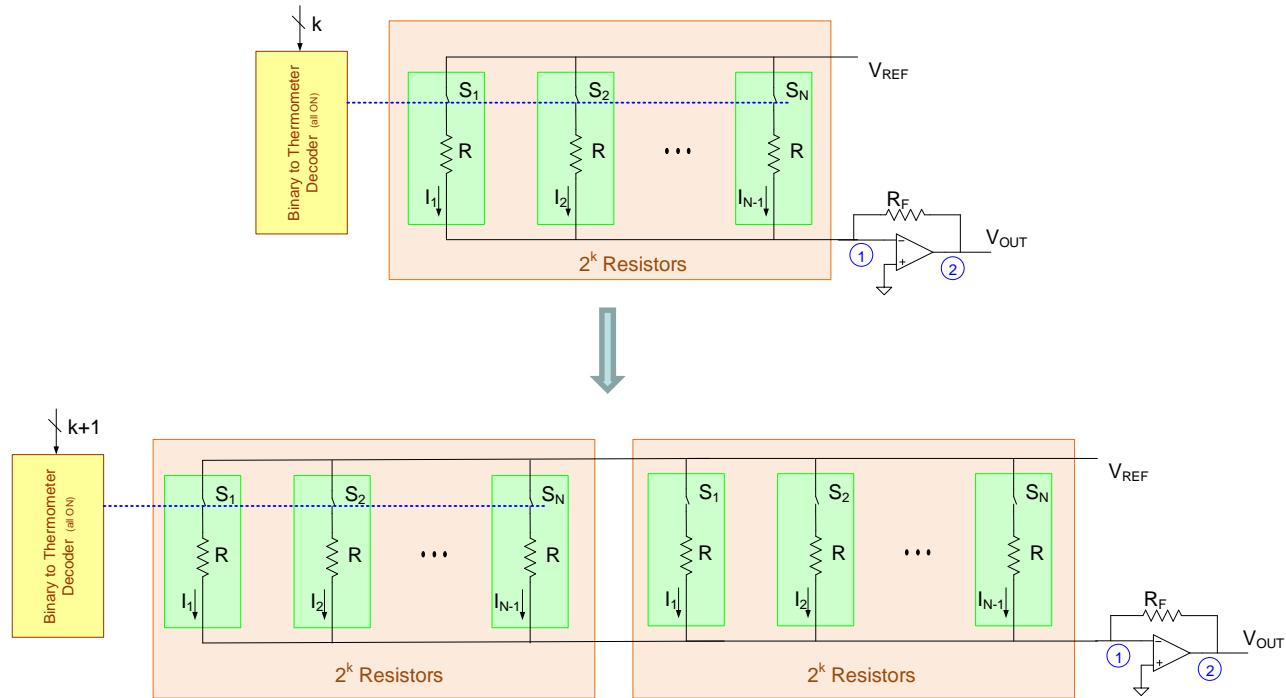


- Need for decoder eliminated !
- DNL may be a major problem
- INL performance about same as thermometer coded if same unit resistors used
- Sizing and layout of switches is critical
- Unary resistor arrays usually used with common-centroid layout(at least for MSB)
- Ratio matching strongly dependent upon area (if common-centroid used to eliminate gradients)
- INL is a random variable with variance approximately proportional to  $\sigma = \frac{A_{PEL}}{\sqrt{A}}$
- Area gets large for good yield with large  $n$

Observe thermometer coding and binary weighted both offer some major advantages and some major limitations



# Current Steering DACs



INL may be poor, typically near mid range

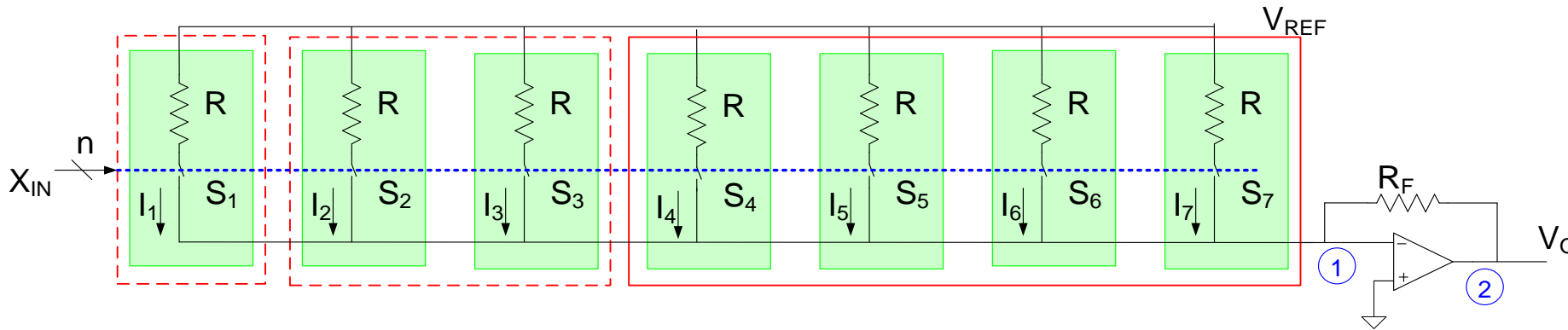
approximately  $\sigma = \frac{A_{PEL}}{\sqrt{A}}$

Consider a k-bit structure that has an acceptable (and desired) yield of Y

Can a k+1 bit structure be easily implemented by simply making 2 copies of the resistor array and adding one bit to the decoder?

The one-afternoon design ?

# Current Steering DACs

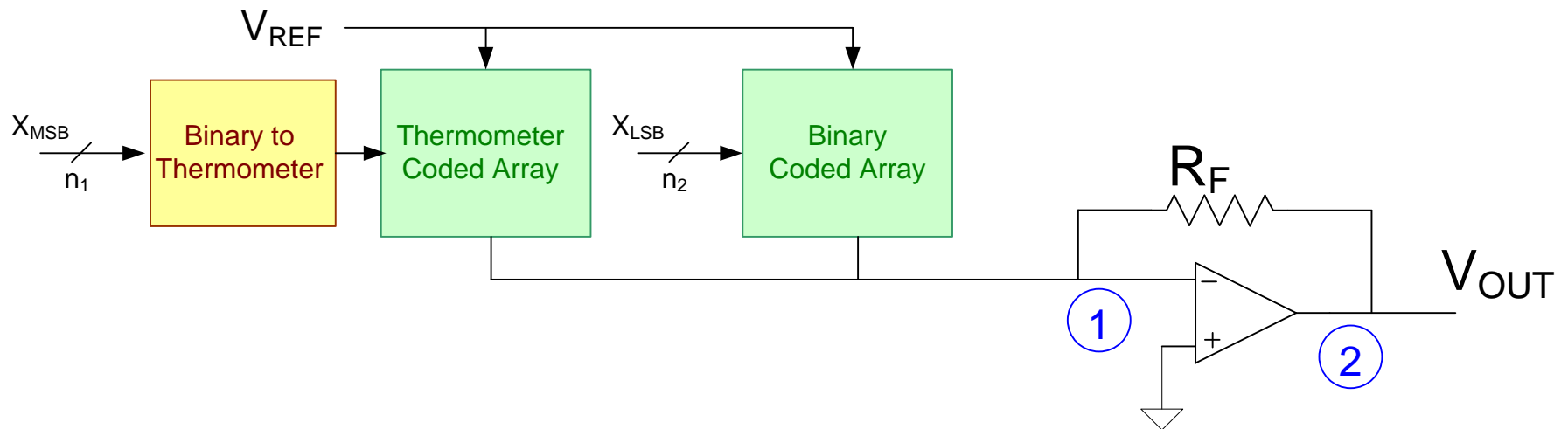


## Binary-Weighted Resistor Arrays

Actual layout of resistors is very important

As stated earlier, bundled unary cells are almost always used

# Current Steering DACs



## Segmented Resistor Arrays

- Combines two types of architectures
- Inherits advantages of both thermometer and binary approach
- Minimizes limitations of both thermometer and binary approach



Stay Safe and Stay Healthy !

End of Lecture 32